



May 2006
FRFET™

FQPF13N50CF / FQPF13N50CF 500V N-Channel MOSFET

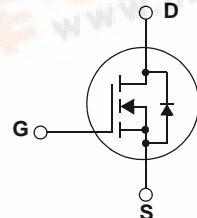
Features

- 13A, 500V, $R_{DS(on)} = 0.54\Omega$ @ $V_{GS} = 10$ V
- Low gate charge (typical 43 nC)
- Low C_{rss} (typical 20pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- Fast recovery body diode (typical 100ns)

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.



Absolute Maximum Ratings

| Symbol | Parameter | FQPF13N50CF | FQPF13N50CF | Unit |
|----------------|--|-------------|-------------|---------------|
| V_{DSS} | Drain-Source Voltage | 500 | | V |
| I_D | Drain Current - Continuous ($T_C = 25^\circ C$) | 13 | 13* | A |
| | - Continuous ($T_C = 100^\circ C$) | 8 | 8* | A |
| I_{DM} | Drain Current - Pulsed (Note 1) | 52 | 52* | A |
| V_{GSS} | Gate-Source voltage | ± 30 | | V |
| E_{AS} | Single Pulsed Avalanche Energy (Note 2) | 530 | | mJ |
| I_{AR} | Avalanche Current (Note 1) | 13 | | A |
| E_{AR} | Repetitive Avalanche Energy (Note 1) | 19.5 | | mJ |
| dv/dt | Peak Diode Recovery dv/dt (Note 3) | 4.5 | | V/ns |
| P_D | Power Dissipation ($T_C = 25^\circ C$) | 195 | 48 | W |
| | - Derate above $25^\circ C$ | 1.56 | 0.39 | W/ $^\circ C$ |
| T_J, T_{STG} | Operating and Storage Temperature Range | -55 to +150 | | $^\circ C$ |
| T_L | Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds | 300 | | $^\circ C$ |

*Drain current limited by maximum junction temperature

Thermal Characteristics

| Symbol | Parameter | FQPF13N50CF | FQPF13N50CF | Unit |
|-----------------|---|-------------|-------------|--------------|
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case | 0.64 | 2.58 | $^\circ C/W$ |
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient | 62.5 | 62.5 | $^\circ C/W$ |

Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|-------------|---------|-----------|------------|----------|
| FQP13N50CF | FQP13N50CF | TO-220 | - | - | 50 |
| FQPF13N50CF | FQPF13N50CF | TO-220F | - | - | 50 |

Electrical Characteristics

$T_C = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Conditions | Min | Typ | Max | Units | |
|---|---|---|-------------|------|------|--------------------------|--|
| Off Characteristics | | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{\text{GS}} = 0\text{V}$, $I_D = 250\mu\text{A}$, $T_J = 25^\circ\text{C}$ | 500 | -- | -- | V | |
| $\Delta \text{BV}_{\text{DSS}} / \Delta T_J$ | Breakdown Voltage Temperature Coefficient | $I_D = 250\mu\text{A}$, Referenced to 25°C | -- | 0.5 | -- | V°C | |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{\text{DS}} = 500\text{V}$, $V_{\text{GS}} = 0\text{V}$ | -- | -- | 10 | μA | |
| | | $V_{\text{DS}} = 400\text{V}$, $T_C = 125^\circ\text{C}$ | -- | -- | 100 | μA | |
| I_{GSSF} | Gate-Body Leakage Current, Forward | $V_{\text{GS}} = 30\text{V}$, $V_{\text{DS}} = 0\text{V}$ | -- | -- | 100 | nA | |
| I_{GSSR} | Gate-Body Leakage Current, Reverse | $V_{\text{GS}} = -30\text{V}$, $V_{\text{DS}} = 0\text{V}$ | -- | -- | -100 | nA | |
| On Characteristics | | | | | | | |
| $V_{\text{GS(th)}}$ | Gate Threshold Voltage | $V_{\text{DS}} = V_{\text{GS}}$, $I_D = 250\mu\text{A}$ | 2.0 | -- | 4.0 | V | |
| $R_{\text{DS(on)}}$ | Static Drain-Source On-Resistance | $V_{\text{GS}} = 10\text{V}$, $I_D = 6.5\text{A}$ | -- | 0.43 | 0.54 | Ω | |
| g_{FS} | Forward Transconductance | $V_{\text{DS}} = 40\text{V}$, $I_D = 6.5\text{A}$ | (Note 4) | -- | 15 | -- | |
| C_{iss} | Input Capacitance | $V_{\text{DS}} = 25\text{V}$, $V_{\text{GS}} = 0\text{V}$, $f = 1.0\text{MHz}$ | | 1580 | 2055 | pF | |
| C_{oss} | Output Capacitance | | | 180 | 235 | pF | |
| C_{rss} | Reverse Transfer Capacitance | | | 20 | 25 | pF | |
| Dynamic Characteristics | | | | | | | |
| $t_{\text{d(on)}}$ | Turn-On Delay Time | $V_{\text{DD}} = 250\text{V}$, $I_D = 13\text{A}$ $R_G = 25\Omega$ | -- | 25 | 60 | ns | |
| t_r | Turn-On Rise Time | | -- | 100 | 210 | ns | |
| $t_{\text{d(off)}}$ | Turn-Off Delay Time | | -- | 130 | 270 | ns | |
| t_f | Turn-Off Fall Time | | -- | 100 | 210 | ns | |
| Q_g | Total Gate Charge | | -- | 43 | 56 | nC | |
| Q_{gs} | Gate-Source Charge | $V_{\text{DS}} = 400\text{V}$, $I_D = 13\text{A}$ $V_{\text{GS}} = 10\text{V}$ | -- | 7.5 | -- | nC | |
| Q_{gd} | Gate-Drain Charge | | (Note 4, 5) | 18.5 | -- | nC | |
| Drain-Source Diode Characteristics and Maximum Ratings | | | | | | | |
| I_S | Maximum Continuous Drain-Source Diode Forward Current | | -- | -- | 13 | A | |
| I_{SM} | Maximum Pulsed Drain-Source Diode Forward Current | | -- | -- | 52 | A | |
| V_{SD} | Drain-Source Diode Forward Voltage | $V_{\text{GS}} = 0\text{V}$, $I_S = 13\text{A}$ | -- | -- | 1.4 | V | |
| t_{rr} | Reverse Recovery Time | $V_{\text{GS}} = 0\text{V}$, $I_S = 13\text{A}$ $dI/dt = 100\text{A}/\mu\text{s}$ | -- | 100 | 160 | ns | |
| Q_{rr} | Reverse Recovery Charge | | -- | 0.35 | -- | μC | |

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. $L = 5.6\text{mH}$, $I_{AS} = 13\text{A}$, $V_{DD} = 50\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{SD} \leq 13\text{A}$, $dI/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$
4. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

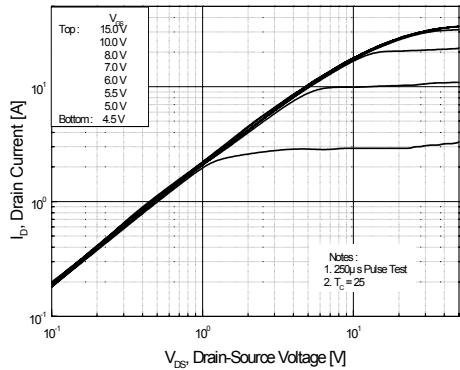


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

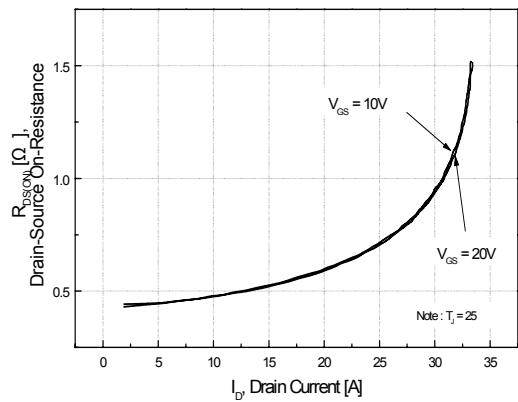


Figure 5. Capacitance Characteristics

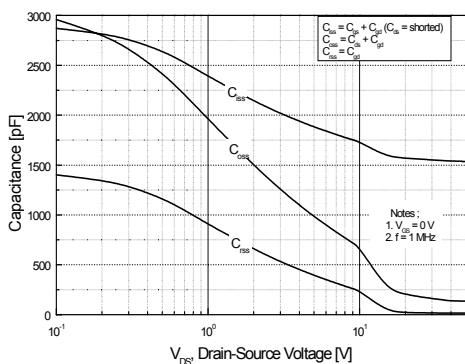


Figure 2. Transfer Characteristics

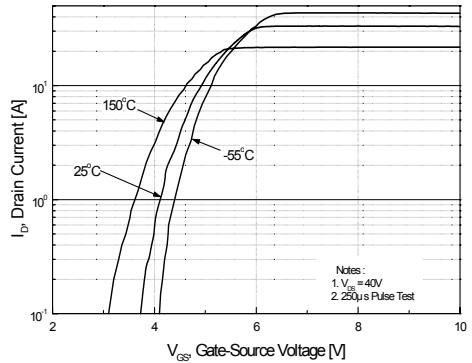


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

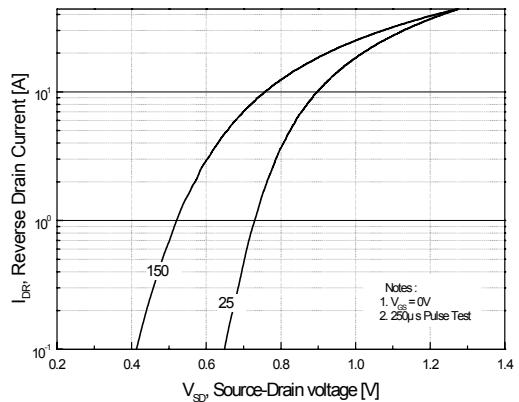
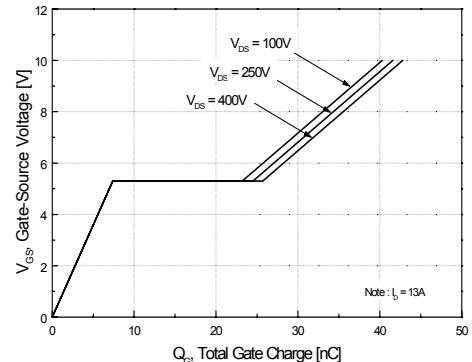


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

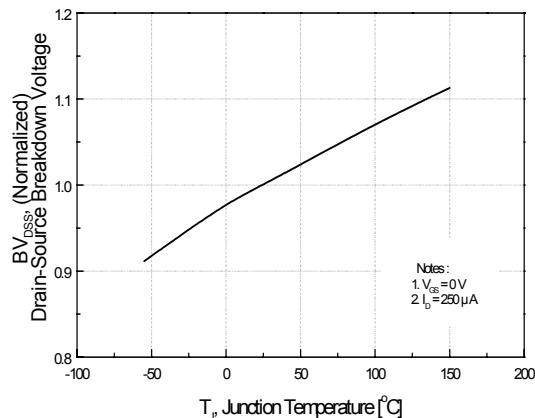


Figure 8. On-Resistance Variation vs. Temperature

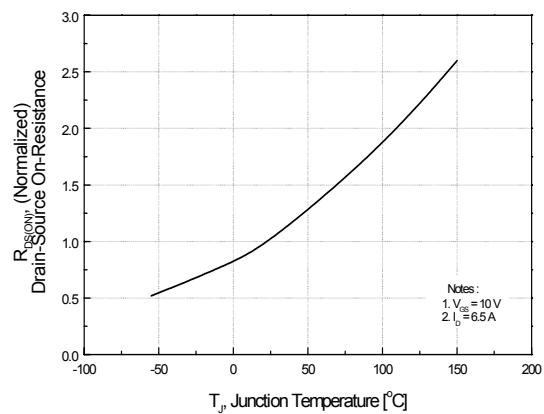


Figure 9-1. Maximum Safe Operating Area for FQP13N50CF

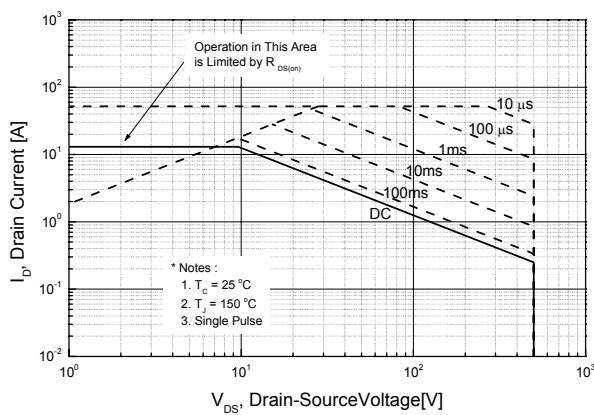


Figure 9-2. Maximum Safe Operating Area for FQPF13N50CF

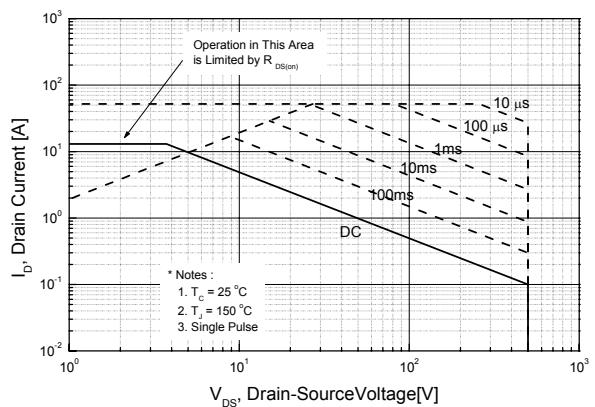
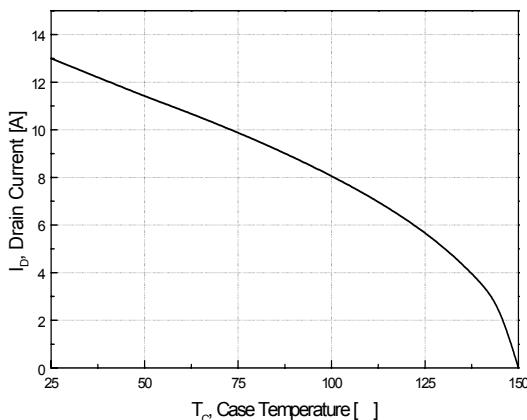


Figure 10. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 11-1. Transient Thermal Response Curve for FQP13N50CF

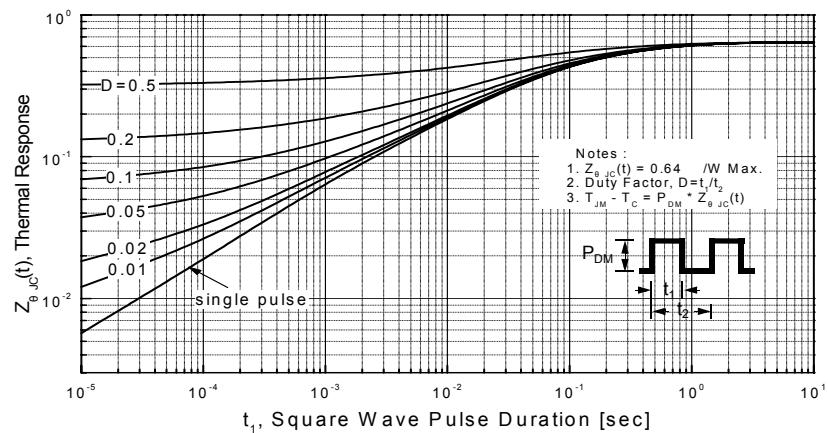
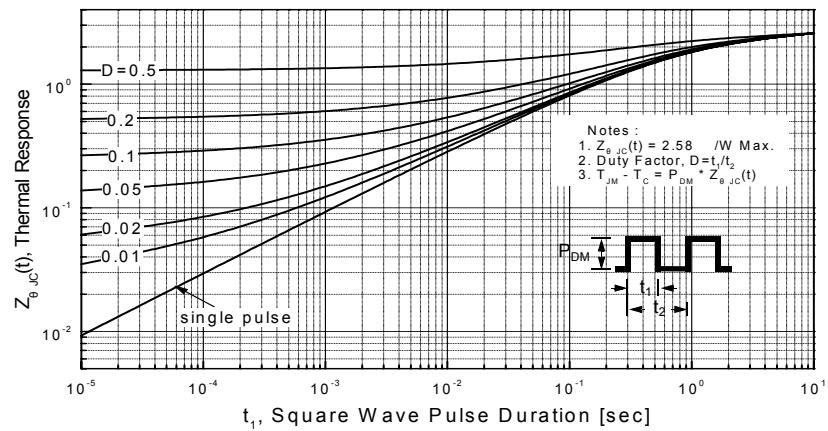
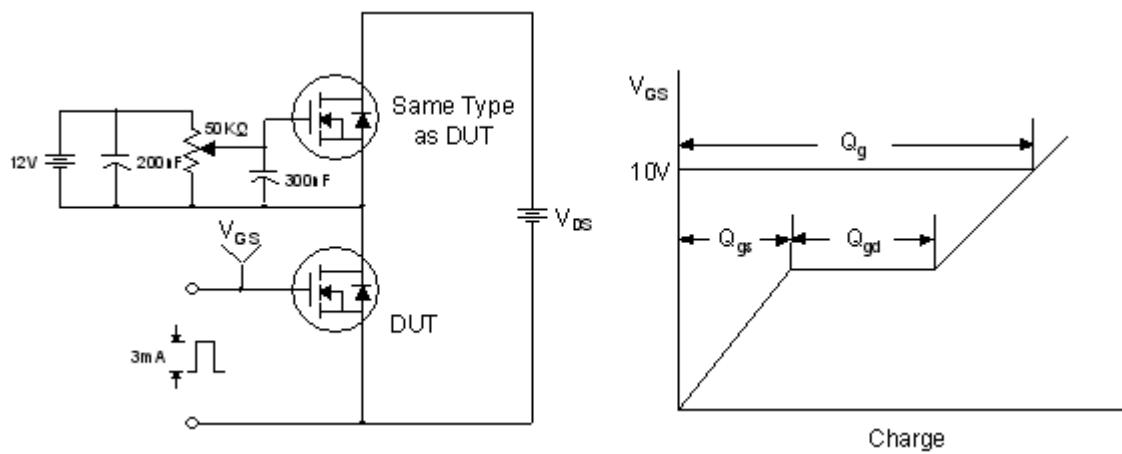


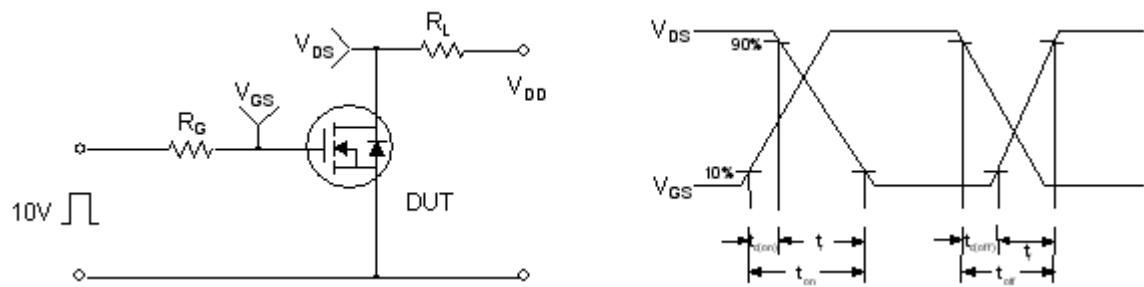
Figure 11-2. Transient Thermal Response Curve for FQPF13N50CF



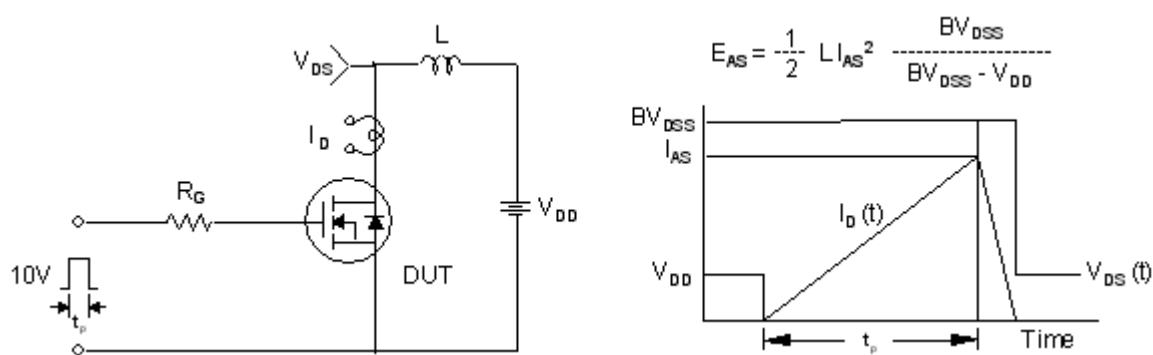
Gate Charge Test Circuit & Waveform



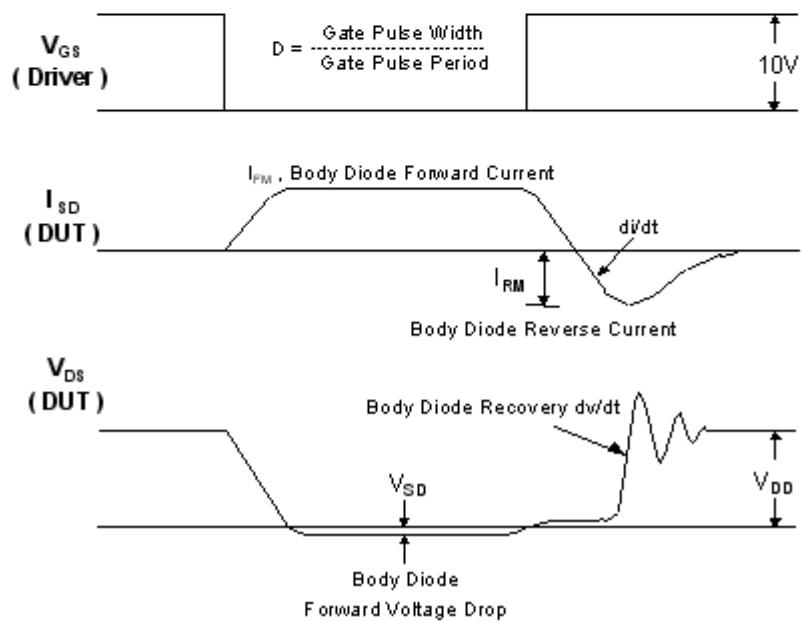
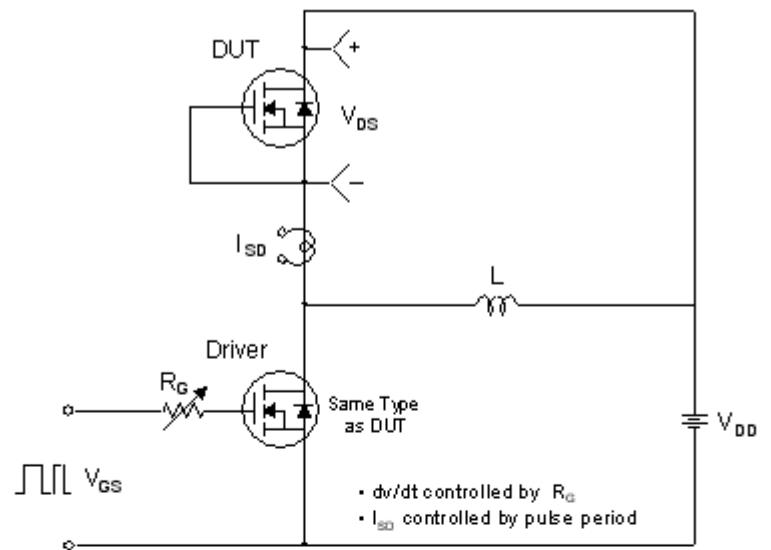
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

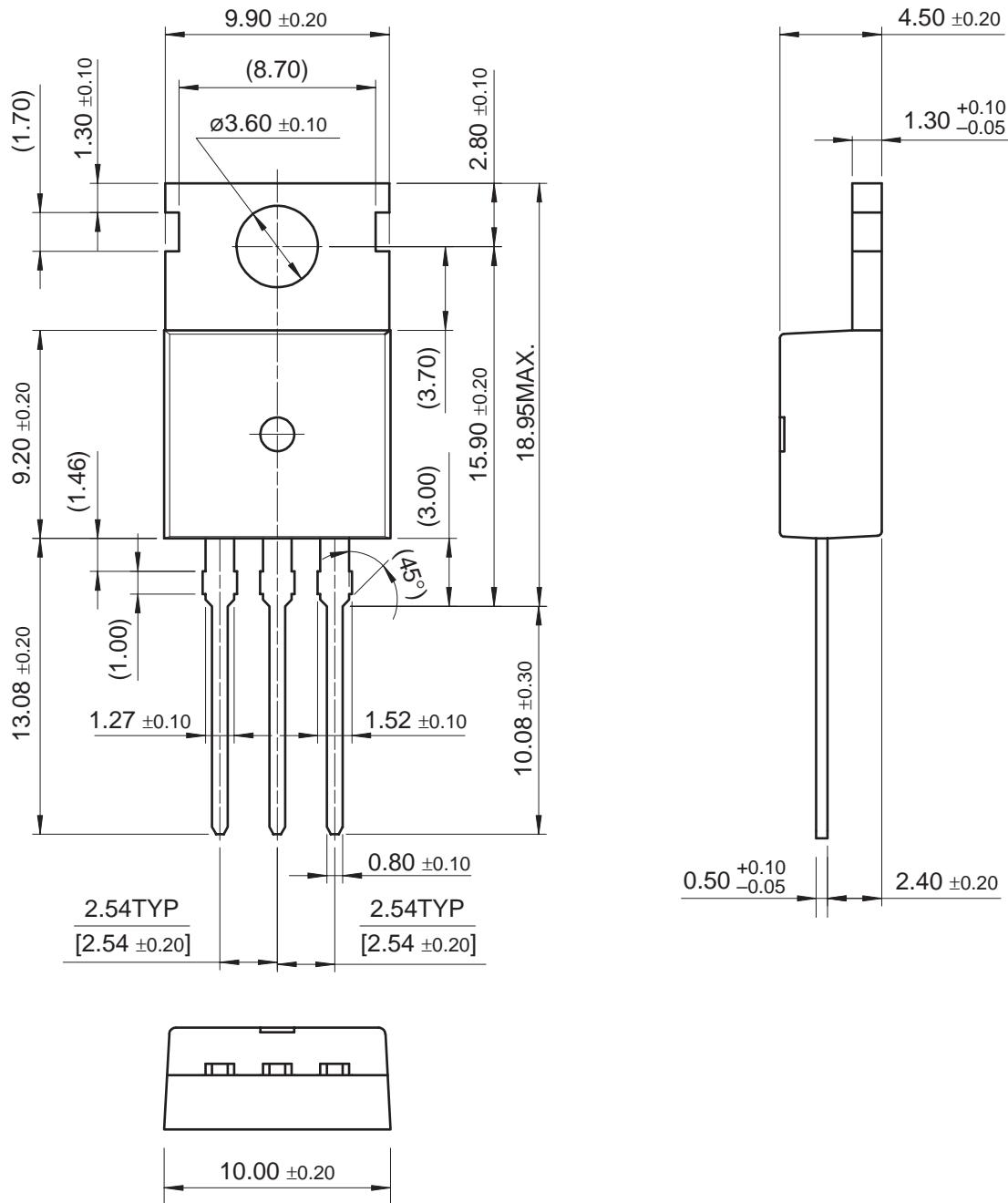


Peak Diode Recovery dv/dt Test Circuit & Waveforms



Mechanical Dimensions

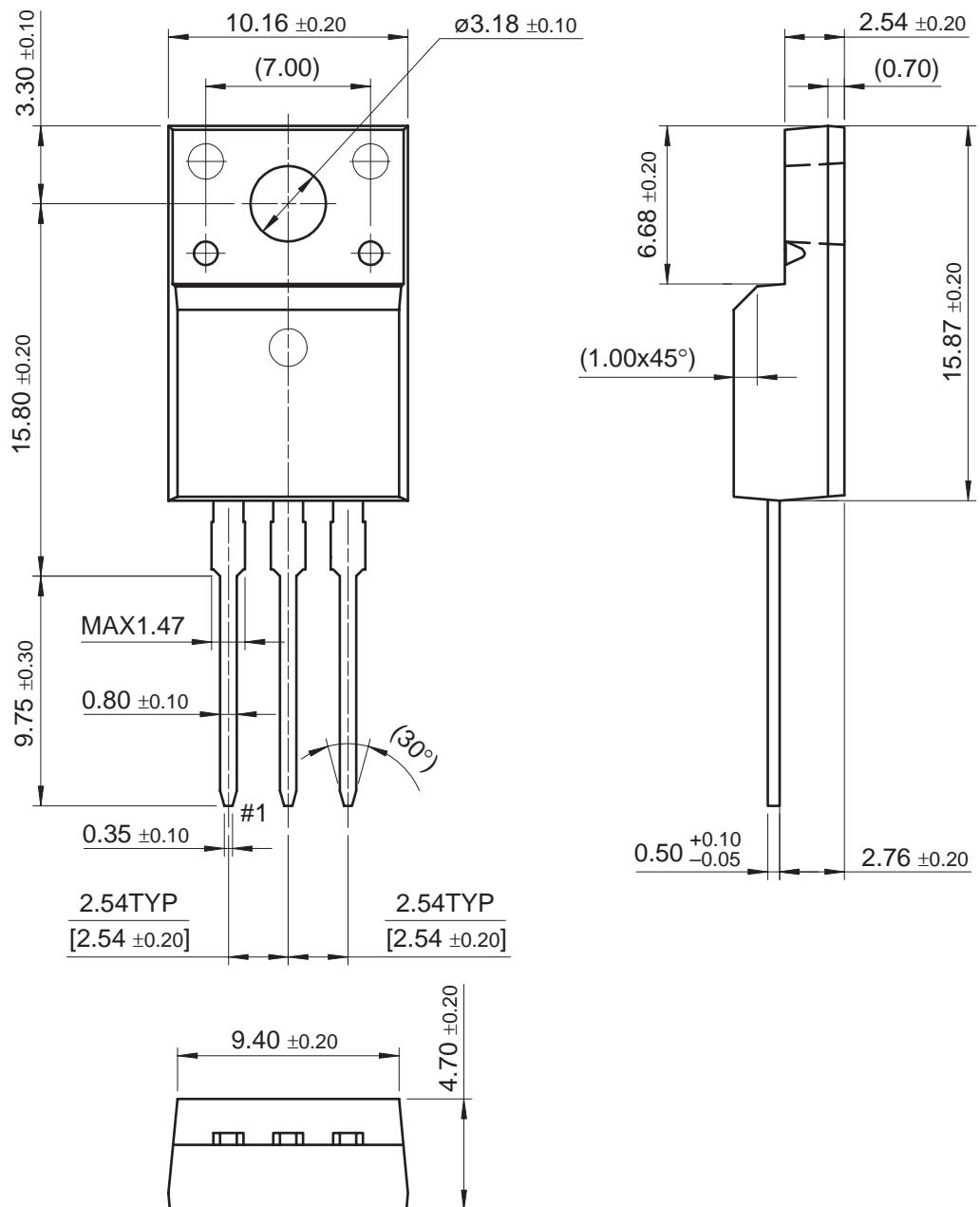
TO-220



Dimensions in Millimeters

Mechanical Dimensions (Continued)

TO-220F



Dimensions in Millimeters

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